### Absolute Maximum Ratings $T_C = 25^{\circ}C$ , Unless Otherwise Specified

	IRFP450	UNITS
Drain to Source Voltage (Note 1) V <sub>DS</sub>	500	V
Drain to Gate Voltage ( $R_{GS}$ = 20k $\Omega$ ) (Note 1)	500	V
Continuous Drain Current	14	А
$T_{C} = 100^{\circ}C$ $I_{D}$	8.8	А
Pulsed Drain Current (Note 3)	56	А
Gate to Source Voltage V <sub>GS</sub>	±20	V
Maximum Power Dissipation	180	W
Linear Derating Factor	1.44	W/ <sup>o</sup> C
Single Pulse Avalanche Energy Rating (Note 4) E <sub>AS</sub>	860	mJ
Operating and Storage Temperature	-55 to 150	°C
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10s	300	°C
Package Body for 10s, See Techbrief 334	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1.  $T_J = 25^{\circ}C$  to  $125^{\circ}C$ .

# **Electrical Specifications** $T_C = 25^{\circ}C$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CON	DITIONS	MIN	ТҮР	MAX	UNITS
Drain to Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V (Figure 10)		500	-	-	V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \mu A$		2.0	-	4.0	V
Zero Gate Voltage Drain Current	IDSS	$V_{DS}$ = Rated BV <sub>DSS</sub> , $V_{GS}$ = 0V $V_{DS}$ = 0.8 x Rated BV <sub>DSS</sub> , $V_{GS}$ = 0V, $T_J$ = 125°C		-	-	25	μA
				-	-	250	μA
On-State Drain Current (Note 2)	I <sub>D(ON)</sub>	V <sub>DS</sub> > I <sub>D(ON)</sub> x r <sub>DS(ON)MAX</sub>	, V <sub>GS</sub> = 10V	14	-	-	A
Gate to Source Leakage Current	I <sub>GSS</sub>	$V_{GS} = \pm 20V$		-	-	±100	nA
On Resistance (Note 2)	r <sub>DS(ON)</sub>	$I_D = 7.9A$ , $V_{GS} = 10V$ (Figure	res 8, 9)	-	0.3	0.4	Ω
Forward Transconductance (Note 2)	9fs	$V_{DS} \ge 50V$ , $I_D = 7.9A$ (Figur	re 12)	9.3	13.8	-	S
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{DD} = 250V, I_D \approx 14A, V_{GS} = 10V, R_{GS} = 6.1\Omega,$		-	16	27	ns
Rise Time	t <sub>r</sub>	$R_L = 17.4\Omega$ MOSFET Switc Essentially Independent of 0		-	45	66	ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>	Losentially independent of C	operating remperature	-	68	100	ns
Fall Time	t <sub>f</sub>	-		-	41	60	ns
Total Gate Charge (Gate to Source + Gate to Drain)	Q <sub>g(TOT)</sub>	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10V, \ I_D \approx 14A, \ V_{DS} = 0.8 \ x \ Rated \ BV_{DSS} \\ I_{G(REF)} = 1.5mA \ (Figure \ 14) \ Gate \ Charge \ is \\ Essentially \ Independent \ of \ OperatingTemperature \end{array}$		-	82	130	nC
Gate to Source Charge	Q <sub>gs</sub>			-	12	-	nC
Gate to Drain "Miller" Charge	Q <sub>gd</sub>			-	42	-	nC
Input Capacitance	C <sub>ISS</sub>	$V_{DS} = 25V, V_{GS} = 0V, f = 1MHz$ (Figure 11)		-	2000	-	pF
Output Capacitance	C <sub>OSS</sub>			-	400	-	pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			-	100	-	pF
Internal Drain Inductance	LD	Measured from the Contact Screw on Header Closer to Source and Gate Pins to Center of Die	Modified MOSFET Symbol Showing the Internal Device Inductances	-	5.0	-	nH
Internal Source Inductance	LS	Measured from the Source Lead, 6.0mm (0.25in) from Header to Source Bonding Pad	G C C C C C C C C C C C C C C C C C C C	-	12.5	-	nH
Thermal Resistance, Junction to Case	R <sub>θJC</sub>			-	-	0.70	°C/W
Thermal Resistance, Junction to Ambient	R <sub>0JA</sub>	Free Air Operation		-	-	30	°C/W

### **Source to Drain Diode Specifications**

PARAMETER	SYMBOL	TEST CONDI	ITIONS	MIN	ТҮР	MAX	UNITS
Continuous Source to Drain Current	I <sub>SD</sub>	Modified MOSFET Symbol		-	-	14	A
Pulse Source to Drain Current (Note 3)	ISDM	Showing the Integral Reverse P-N Junction Rectifier	Go U S	-	-	56	A
Source to Drain Diode Voltage (Note 2)	V <sub>SD</sub>	$T_J = 25^{\circ}C$ , $I_{SD} = 14A$ , $V_{GS} = 0V$ (Figure 13)		-	-	1.4	V
Reverse Recovery Time	t <sub>rr</sub>	$T_{J} = 150^{o}C$ , $I_{SD} = 13A$ , $dI_{SD}/dt = 100A/\mu s$		-	1300	-	ns
Reverse Recovery Charge	Q <sub>RR</sub>	$T_J = 150^{o}C$ , $I_{SD} = 13A$ , $dI_{SD}/dt = 100A/\mu s$		-	7.4	-	μC

NOTES:

2. Pulse test: pulse width  $\leq$  300 $\mu$ s, duty cycle  $\leq$  2%.

- 3. Repetitive rating: pulse width limited by Max junction temperature. See Transient Thermal Impedance curve (Figure 3).
- 4.  $V_{DD}$  = 50V, starting T<sub>J</sub> = 25<sup>o</sup>C, L = 7.9mH, R<sub>G</sub> = 25 $\Omega$ , peak I<sub>AS</sub> = 14A.



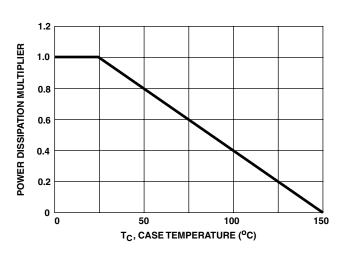


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

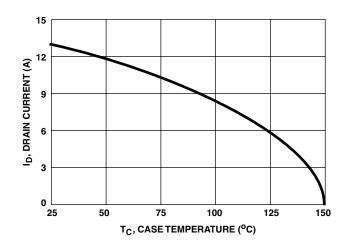
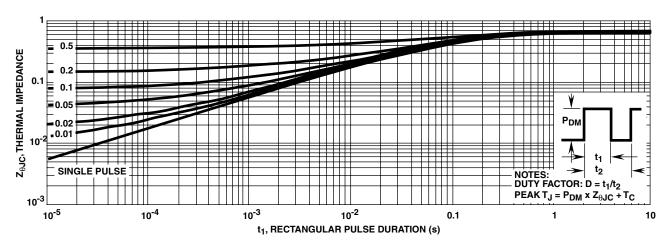


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE





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# Typical Performance Curves Unless Otherwise Specified (Continued)

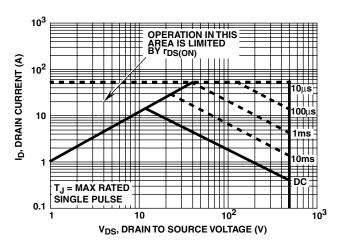


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

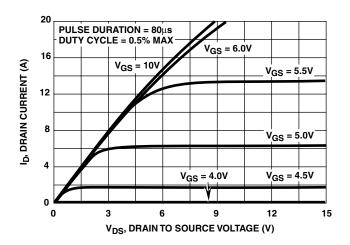
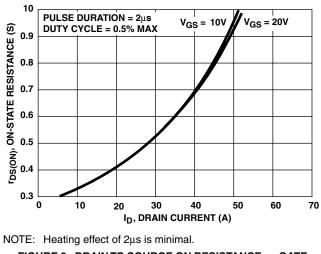
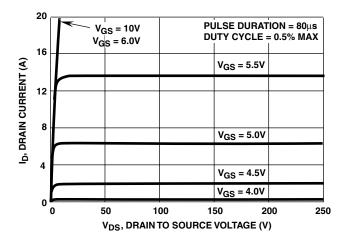


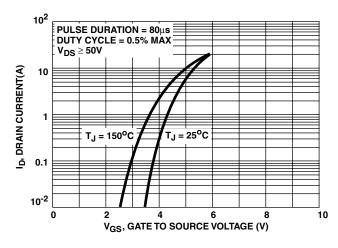
FIGURE 6. SATURATION CHARACTERISTICS













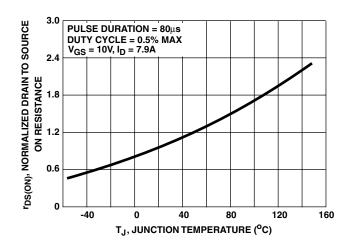
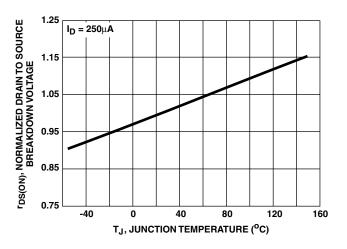


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

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## Typical Performance Curves Unless Otherwise Specified (Continued)





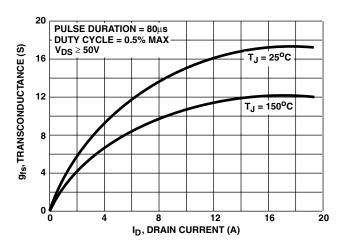


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

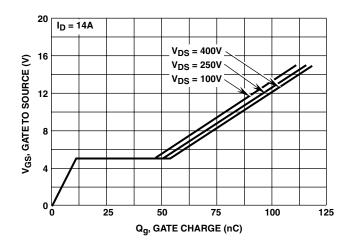


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

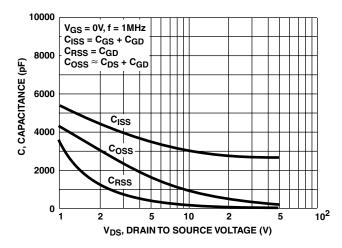


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

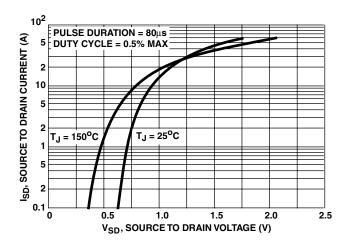


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

# Test Circuits and Waveforms

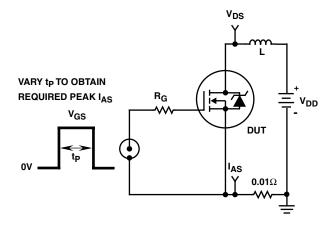


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

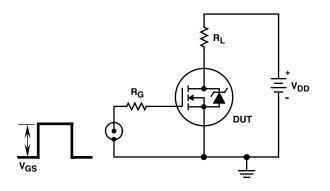


FIGURE 17. SWITCHING TIME TEST CIRCUIT

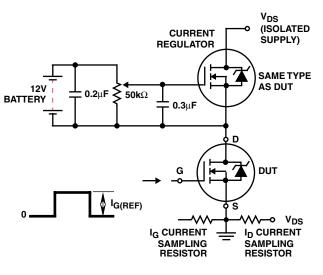


FIGURE 19. GATE CHARGE TEST CIRCUIT



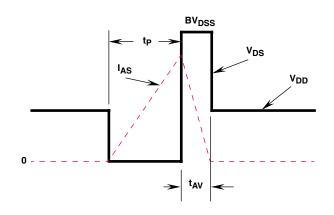


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

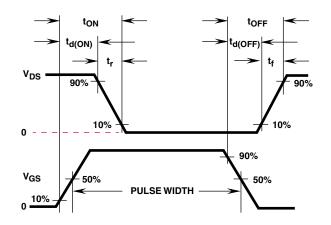
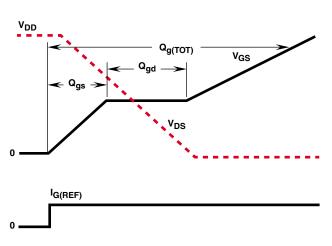


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS



#### FIGURE 20. GATE CHARGE WAVEFORMS

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